

L Number	Hits	Search Text	DB	Time stamp
1	505	250/423F	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:54
2	1	250/423F AND (pipette and nanotube).CLM.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:54
3	1	250/423F AND (scanning adj electron adj microscope and point adj source).CLM.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:53
4	1	250/423F AND ((scanning adj electron adj microscope) and conical\$3 and point adj source).CLM.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:53
5	0	250/442.11 AND ((scanning adj electron adj microscope) and conical\$3 and point adj source).CLM.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:53
6	0	250/442.11 AND (scanning adj electron adj microscope and point adj source).CLM.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:53
7	0	250/442.11 AND (pipette and nanotube).CLM.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:54

8	748	250/442.11		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:54
-	0	superconduction and carbon adj nanotube		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/07 17:52
-	41	superconducting and carbon adj nanotube		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/07 17:53
-	30	(superconducting and carbon adj nanotube) and (electron adj (source or beam))		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/08 16:32
-	1	"20040079892"		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 13:59
-	12	(US-5393647-\$ or US-5587586-\$ or US-5654548-\$ or US-6005247-\$ or US-6043491-\$ or US-6020677-\$).did. or (JP-11067139-\$ or US-6005247-\$ or US-6020677-\$ or US-5654548-\$ or EP-731981-\$ or US-5393647-\$).did.		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 17:33
-	506	miniature and electron adj microscope		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 17:36
-	4	metallic-type adj carbon adj3 nanotube		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 17:58

-	8	(miniature and electron adj microscope) and carbon adj3 nan tube	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 18:12
-	5	carbon adj3 nanotube WITH conductive adj coating	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 18:17
-	10	carbon adj3 nanotube SAME conductive adj coating	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 18:37
-	130	scanning adj electron adj microscope and point adj source	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:50
-	2493	scanning adj electron adj microscope and (conical\$3 or taper\$3 or cone)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 18:41
-	2493	(scanning adj electron adj microscope) and (conical\$3 or taper\$3 or cone)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 18:42
-	1968	(scanning adj electron adj microscope) and (conical\$3 or taper\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 18:42
-	913	(scanning adj electron adj microscope) and (conical\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 18:43

-	33	(scanning adj electron adj mi rosc pe) and c nical\$3 and p int adj source	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:52
-	301	(scanning adj electron adj microscope) and pipette	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 18:57
-	4	(scanning adj electron adj microscope) and pipette and point adj source	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/25 19:00
-	13	(scanning adj electron adj microscope) and pipette and nanotube	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:48
-	2	5587586.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 08:49
-	2	5587586.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 10:46